

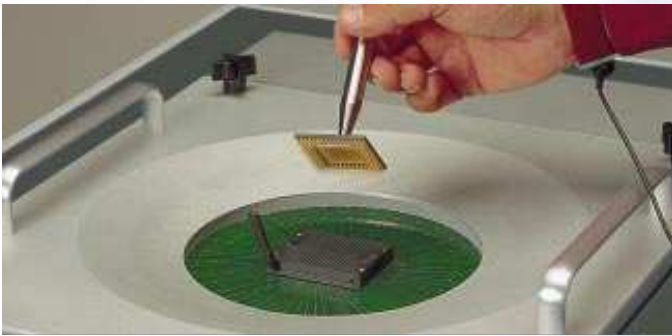


ESD and Latch-Up Test Services



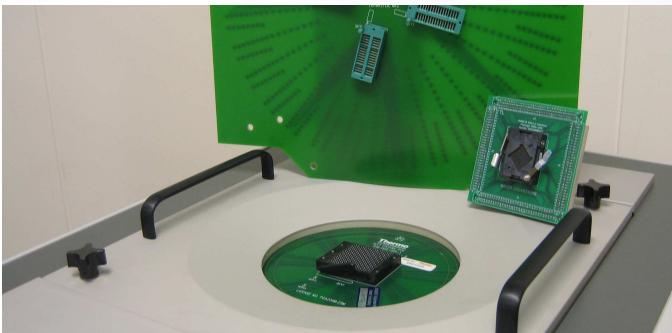
Keytek Zapmaster Mk.2 SE

- Quick turn-around times
- HBM & MM testing up to 512 pins
- Spot Measurement capability
- Curve Tracing capability
- Six separate V/I supplies
- Latch-Up testing with 64k / pin



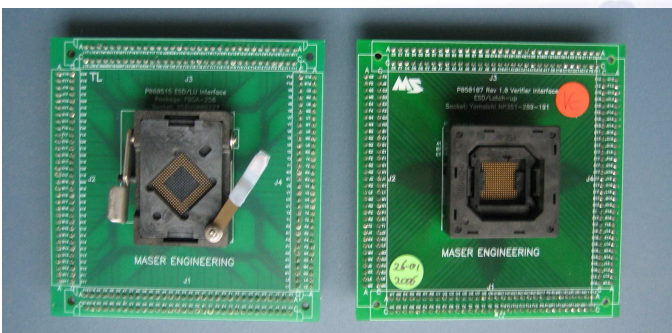
Human Body Model

- 50V to 8kV
- JEDEC EIA/JESD22-A114
- ESDA STM 5.1
- MIL-SDT 883
- AEC Q100-002



Machine Model

- 50V to 2kV
- JEDEC EIA/JESD22-A115
- ESDA STM 5.2
- AEC Q100-003



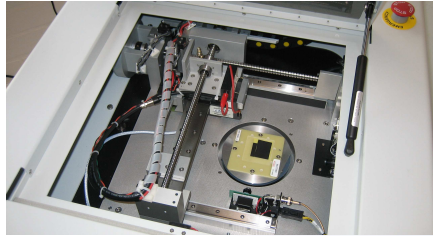
Latch-Up

- JEDEC EIA/JESD78
- AEC Q100-004
- Including preconditioning, state read-back & full control of each pin

ESD and LU test service 2010-1

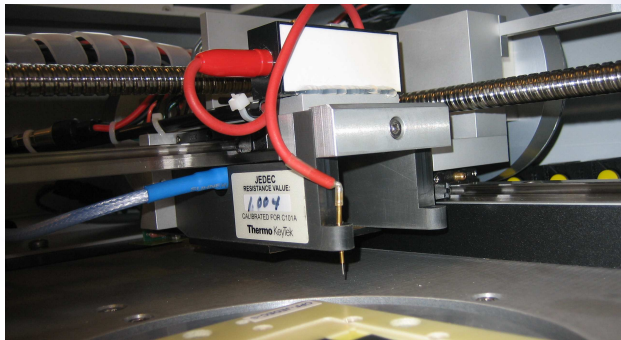


ESD and Latch-Up Test Services



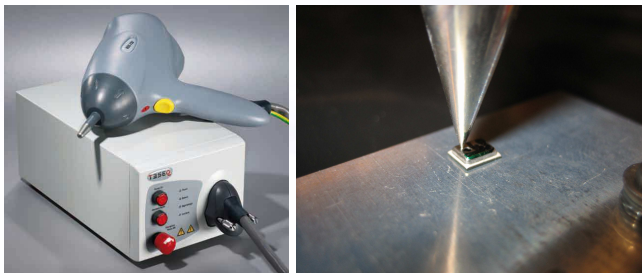
Keytek RCDM3

- Quick turnaround times
- Field or Direct Charge Method
- Positioning accuracy of 0.01mm
- Built in vacuum system
- Allows the introduction of inert gases



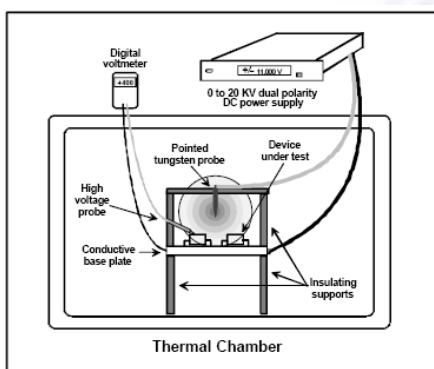
Charge Device Model

- 0V to 4kV
- JEDEC EIA/JESD22-C101
- ESDA STM 5.3.1
- AEC Q100-011



ESD system level test

- Tesseq/Schaffner NSG 438
- Air/contact 0.2 to 30 kV
- IEC 61000-4-2 and ANSI, SAE, ISO, MIL
- Applicable for Electronic systems and modules



Electro-Thermally Induced Parasitic Gate Leakage

- Test to determine susceptibility to Electro-Thermally Induced Parasitic Gate Leakage
- AEC-Q100-006
- E-field $\pm 400V$
- Test @ 155°C

ESD and LU test service 2010-1